
Surface chemical analysis — Scanning probe microscopy — Procedure for the determination of elastic moduli for compliant materials using atomic force microscope and the two-point JKR method

*Analyse chimique des surfaces — Microscopie à sonde locale —
Lignes directrices pour la détermination des modules d'élasticité des
matériaux souples en utilisant un microscope à force atomique*





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CP 401 • Ch. de Blandonnet 8
CH-1214 Vernier, Geneva
Phone: +41 22 749 01 11
Fax: +41 22 749 09 47
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